

---

*Supplementary information (SI) for*

**Electrostatic gating dependent multiple band alignments in  
ferroelectric VS<sub>2</sub>/Ga<sub>2</sub>O<sub>3</sub> van der Waals heterostructures**

Yunlai Zhu <sup>a</sup>, Zihan Qu <sup>a</sup>, Xiaoteng Wang <sup>a</sup>, Jishun Zhang <sup>a</sup>, Zuheng Wu <sup>a</sup>, Zuyu Xu <sup>a</sup>,  
Fei Yang <sup>a</sup>, Jun Wang <sup>a</sup> and Yuehua Dai <sup>a\*</sup>

<sup>a</sup> School of Integrated Circuits, Anhui University, Hefei, Anhui, 230601, China.

**Corresponding Author**

\*E-mail: daiyuehua2013@163.com (Y.-H. Dai)

**Table S1** Optimized lattice constant ( $a=b$ ), interlayer distance ( $d$ ), the energy difference ( $\Delta E$ ) with the lowest energy states under different polarizations, binding energy ( $E_b$ ) of 2D VS<sub>2</sub>/Ga<sub>2</sub>O<sub>3</sub> heterostructures without vdW correction.

Structure	Stacking	$a=b(\text{\AA})$	$d_{min}(\text{\AA})$	$\Delta E$ (meV)	$E_b(\text{meV}/\text{\AA}^2)$
VS <sub>2</sub> /Ga <sub>2</sub> O <sub>3</sub>	U <sub>1</sub>	3.125	3.826	4.7	-3.547
	U <sub>2</sub>	3.125	3.432	0	-4.174
	U <sub>3</sub>	3.125	3.475	0.4	-4.138
	D <sub>1</sub>	3.123	3.688	0	-1.421
	D <sub>2</sub>	3.132	3.791	0.3	-1.365
	D <sub>3</sub>	3.125	4.042	1.7	-1.182

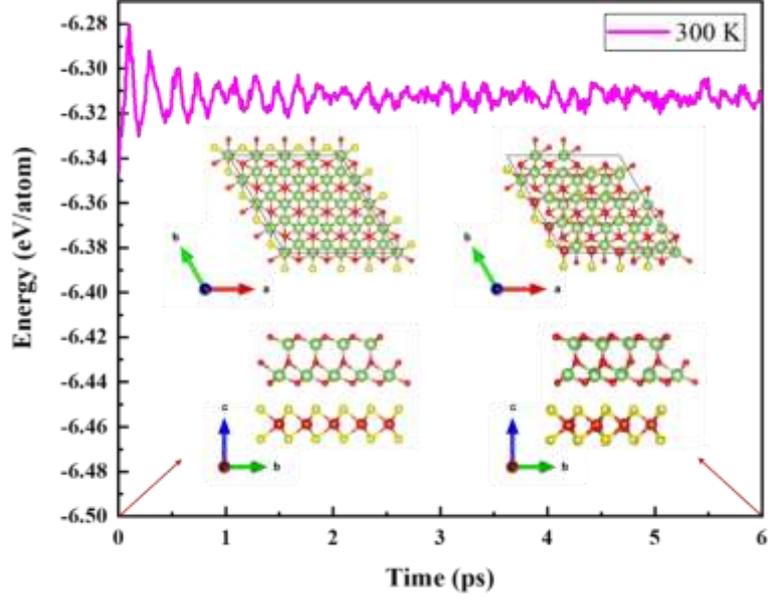
To explore the effect of DFT-D2 vdW method on 2D VS<sub>2</sub>/Ga<sub>2</sub>O<sub>3</sub> heterostructures, the structural properties without vdW correction were also calculated. The parameters of optimized lattice constants ( $a$ ), the interlayer distance ( $d$ ), the energy difference compared with the lowest energy states in different polarized direction ( $\Delta E$ ) and the binding energy ( $E_b$ ) without vdW correction are listed in **Table S1**. Compared with the results using DFT-D2 method, there is an evident increasement in the interlayer distance,

even reaching up to 4 Å for VS<sub>2</sub>/P↑Ga<sub>2</sub>O<sub>3</sub> heterostructure in D<sub>3</sub> stacking. In addition, the energy difference  $\Delta E$  under different polarizations is not obvious and the binding energy  $E_b$  is too small, implying there is nearly no vdW interlayer interactions in 2D VS<sub>2</sub>/Ga<sub>2</sub>O<sub>3</sub> heterostructures, which doesn't agree with the fact.

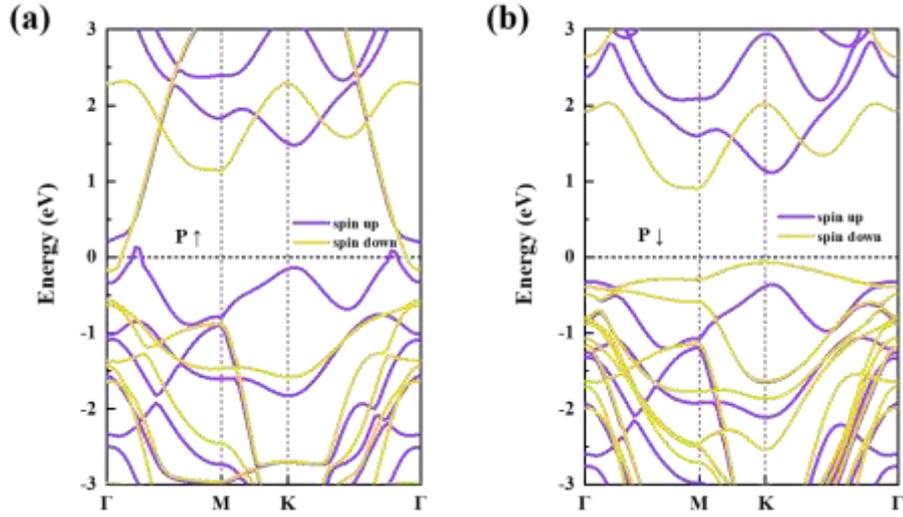
In addition, the DFT-D3 method was also adopted to calculate the 2D VS<sub>2</sub>/Ga<sub>2</sub>O<sub>3</sub> heterostructures. The parameters of optimized lattice constants ( $a$ ), the interlayer distance ( $d$ ), the energy difference compared with the lowest energy states in different polarized direction ( $\Delta E$ ) and the binding energy ( $E_b$ ) using DFT-D3 method are listed in **Table S2**. Compared with the results using DFT-D2 method, there are only minor changes in the lattice constants and interlayer distance. Notably, U<sub>3</sub> stacking possesses the most stable structure in the VS<sub>2</sub>/P↑Ga<sub>2</sub>O<sub>3</sub> structure, while D<sub>2</sub> stacking has 0.6 meV lower energy than the D<sub>1</sub> stacking (the most stable one using DFT-D2 method) and becomes the most stable one in the VS<sub>2</sub>/P↓Ga<sub>2</sub>O<sub>3</sub> structure.

**Table S2** Optimized lattice constant ( $a=b$ ), interlayer distance ( $d$ ), the energy difference ( $\Delta E$ ) with the lowest energy states under different polarizations, binding energy ( $E_b$ ) of 2D VS<sub>2</sub>/Ga<sub>2</sub>O<sub>3</sub> heterostructures using the DFT-D3 method.

Structure	Stacking	$a=b(\text{Å})$	$d_{min}(\text{Å})$	$\Delta E$ (meV)	$E_b(\text{meV}/\text{Å}^2)$
VS <sub>2</sub> /Ga <sub>2</sub> O <sub>3</sub>	U <sub>1</sub>	3.111	3.171	61.9	-124.3
	U <sub>2</sub>	3.112	2.857	10.4	-130.3
	U <sub>3</sub>	3.113	2.758	0	-131.4
	D <sub>1</sub>	3.113	2.911	0.6	-127.2
	D <sub>2</sub>	3.113	2.859	0	-127.2
	D <sub>3</sub>	3.111	3.28	53.8	-121.3



**Fig. S1** Total potential energy fluctuation as a function of the AIMD simulation, and the initial and final structures of VS<sub>2</sub>/Ga<sub>2</sub>O<sub>3</sub> vdW heterostructures at 300 K.

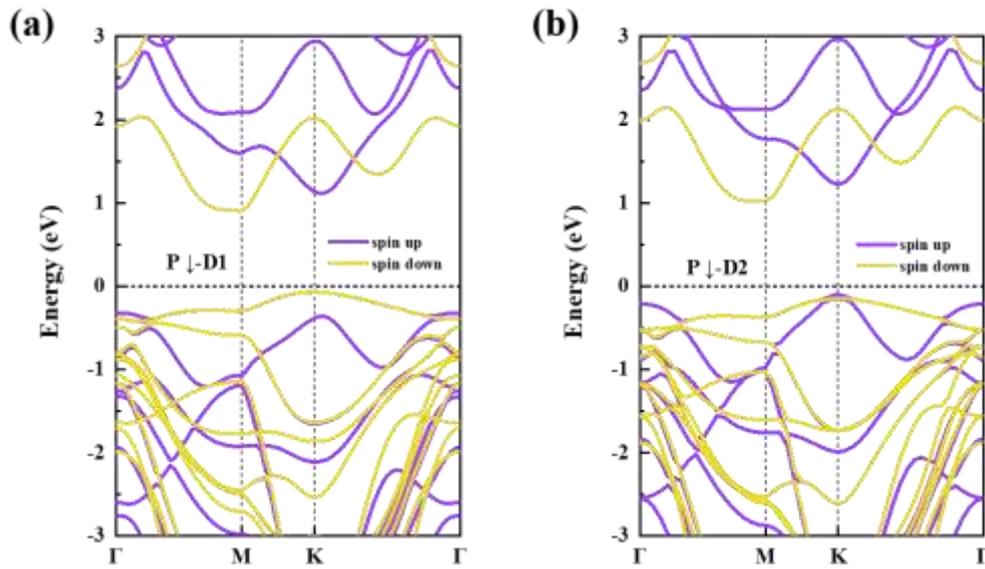


**Fig. S2** Electronic band structures of VS<sub>2</sub>/Ga<sub>2</sub>O<sub>3</sub> with DFT-D3 correction for (a) P<sup>↑</sup> structure and (b) P<sup>↓</sup> structure.

The electronic properties in the most stable one ( $U_3$  and  $D_2$  stacking) under different polarizations using the DFT-D3 method were illustrated in **Fig. S2**. When the polarized direction of Ga<sub>2</sub>O<sub>3</sub> monolayer is upward, the CBM and VBM all overlap the fermi energy, presenting metallic properties. However, when polarized direction is reversed, the CBM and VBM are located at the high-symmetric  $M$  and  $K$  point, respectively, exhibiting semiconducting properties. Obviously, there is also a band

structure reversion from metal to semiconductor due to the ferroelectric polarization reversal, which is consistent with DFT-D2 method.

Furthermore, due to the small energy difference between the  $D_1$  and  $D_2$  stacking, we calculated the electronic band structures of both the two stackings, depicted in Fig. S3. Obviously, these band structures all behave as semiconductors, whose CBM and VBM are located at the high-symmetric  $M$  and  $K$  point, respectively. Taking the optimized energy of  $\text{VS}_2/\text{Ga}_2\text{O}_3$  heterostructures into consideration, the results with the DFT-D2 method own lower energy than those with the DFT-D3 method. Thus, the DFT-D2 vdW correction was adopted in our work.



**Fig. S3** Electronic band structures of  $\text{VS}_2/\text{P}\downarrow\text{Ga}_2\text{O}_3$  structure with DFT-D3 correction in (a)  $D_1$  stacking and (b)  $D_2$  stacking.